

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No. : 10/622,933 Confirmation No: 3481  
Applicant : Chee Hong Liao  
Filed : July 18, 2003  
Title : Method of Processing Test Patterns for an Integrated Circuit  
Art Unit : 2128  
Examiner : Saif A. Alhija  
Docket No. : M&N-IT-465  
Customer No. : 24131

Hon. Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**A M E N D M E N T UNDER 37 CFR § 1.116**

Sir:

Responsive to the final Office action dated April 10, 2007 kindly amend the above-identified application as follows:

- **Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.
- **Remarks** begin on page 9 of this paper.